

<b>Notice of References Cited</b>	Application/Control No. 10/597,939	Applicant(s)/Patent Under Reexamination ZHENG ET AL.	
	Examiner JUN LI	Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-2004/0105789 A1	06-2004	Yamamoto, Tadao	422/130
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Abstract of Shen et al (CN85100996)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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